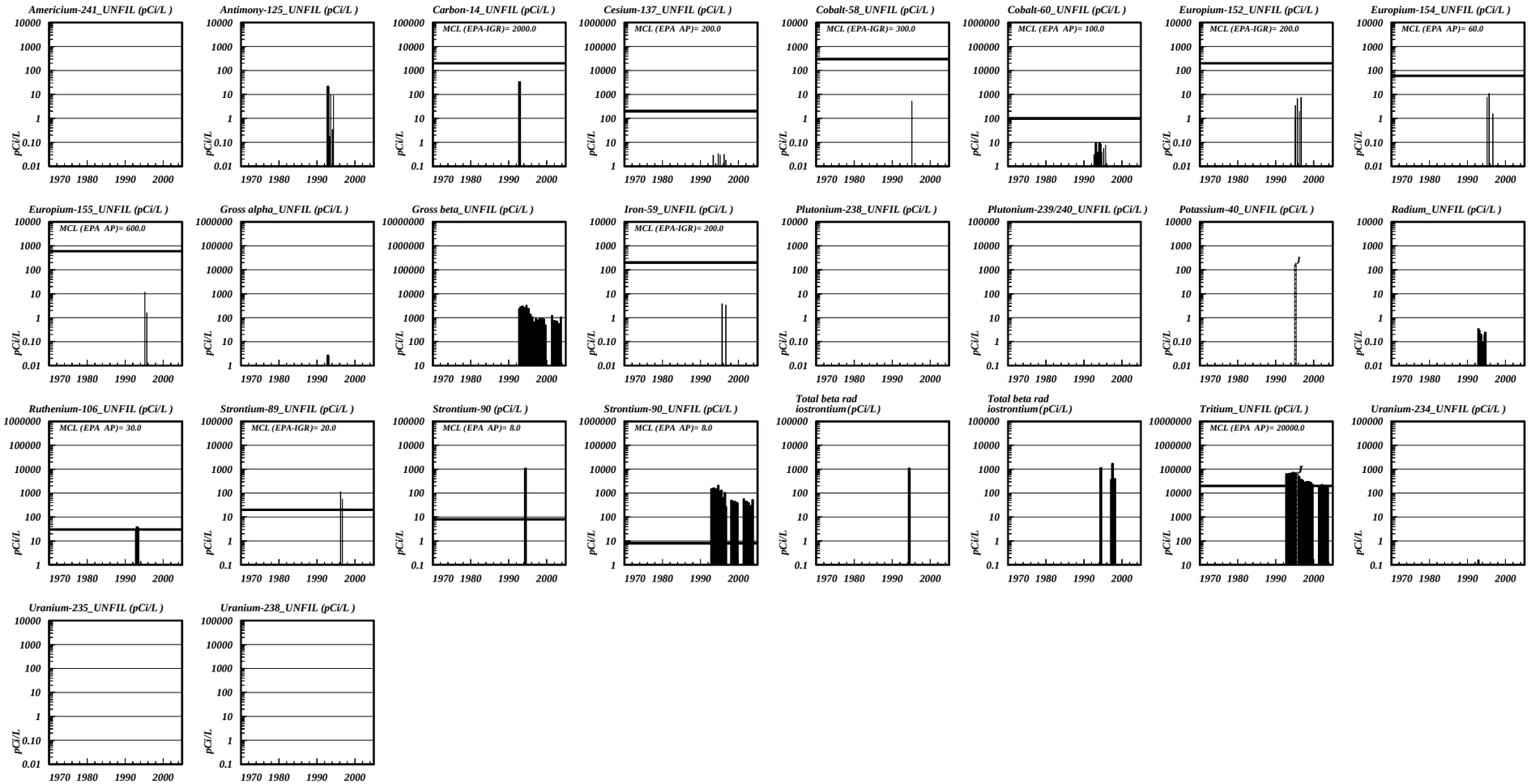
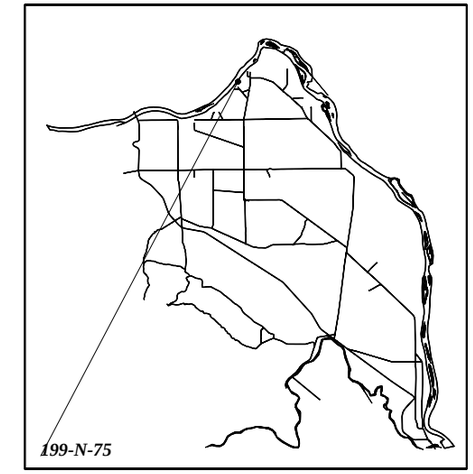
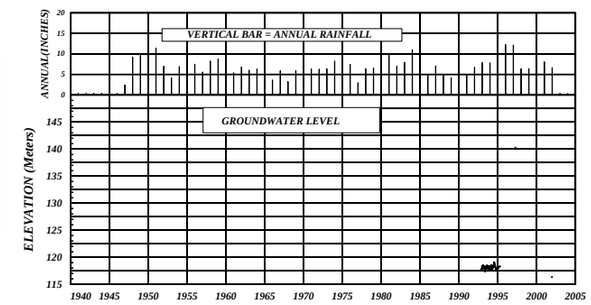
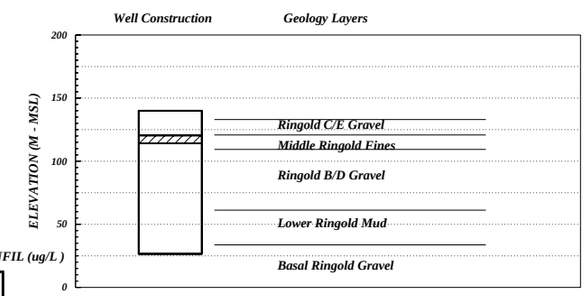
DOE HANFORD SITE - GROUNDWATER QUALITY DATA PLOTS wellseries-100-199 WELL#=199-N-75

RADIONUCLIDES

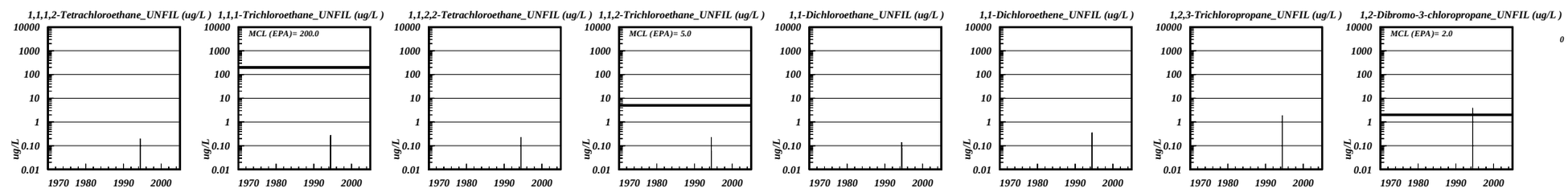








VOLATILE ORGANIC COMPOUNDS



WELLNAME=199-N-75 WELLID=A4718

Well Type=STANDARD Well purpose=EXTRACTION
Owner=DOE ContactBHI Well Adm Compliance=COMPLIANT
X_coor= 571523.60 Y-coor= 150060.70 Datum=NAD83 Date Survey= 7/31/1992
Elevation= 140.008 Datum=NGVD29 Date Survey=07/31/92
Ref_Point_Desc=TOP OF PLATE Ref_Point_side=N Contractor=KEH
Well_Comment= 1301-N LWDF
Total Number of perforation Intervals=1
NPERF#=1 Perf_top= 119.82 Bot= 113.42 MCas_size= 0.00 Perf_cuts= 0.00
Total Number of Screen Intervals=1
Screen#=1 Screen_diam= 4.00 in Top= 19.63 Bottom= 25.85 m Slot_size= 0.01 in
Screen_material=Stainless Steel
Total Number of Seals=6
Seal#=1 Depth_top=-0.15 Bottom= 0.61 m Material=Concrete
Seal#=2 Depth_top= 0.61 Bottom= 2.90 m Material=Cement Grout
Seal#=3 Depth_top= 16.73 Bottom= 18.02 m Material=Bentonite Pellets
More Information is at http://www.envirodataaccess.com/wellfiles/199-N-75.htm

LABORATORY QUALIFIER FLAGS in HEIS are *, >, B, C, D, E, J, L, P, Q, R, W, X, Y, and Z: Review Document. Main Flags are : J=Estimated value:L=Value between IDL and CRQL (estimated):T=Tentatively identified compound:
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EXPLANATION: THICK FILLED BARS=Value Above Detection Limit:THIN BARS=Value Below Detection Limit:HATCHED BARS=Value With Data Qualifier Flag

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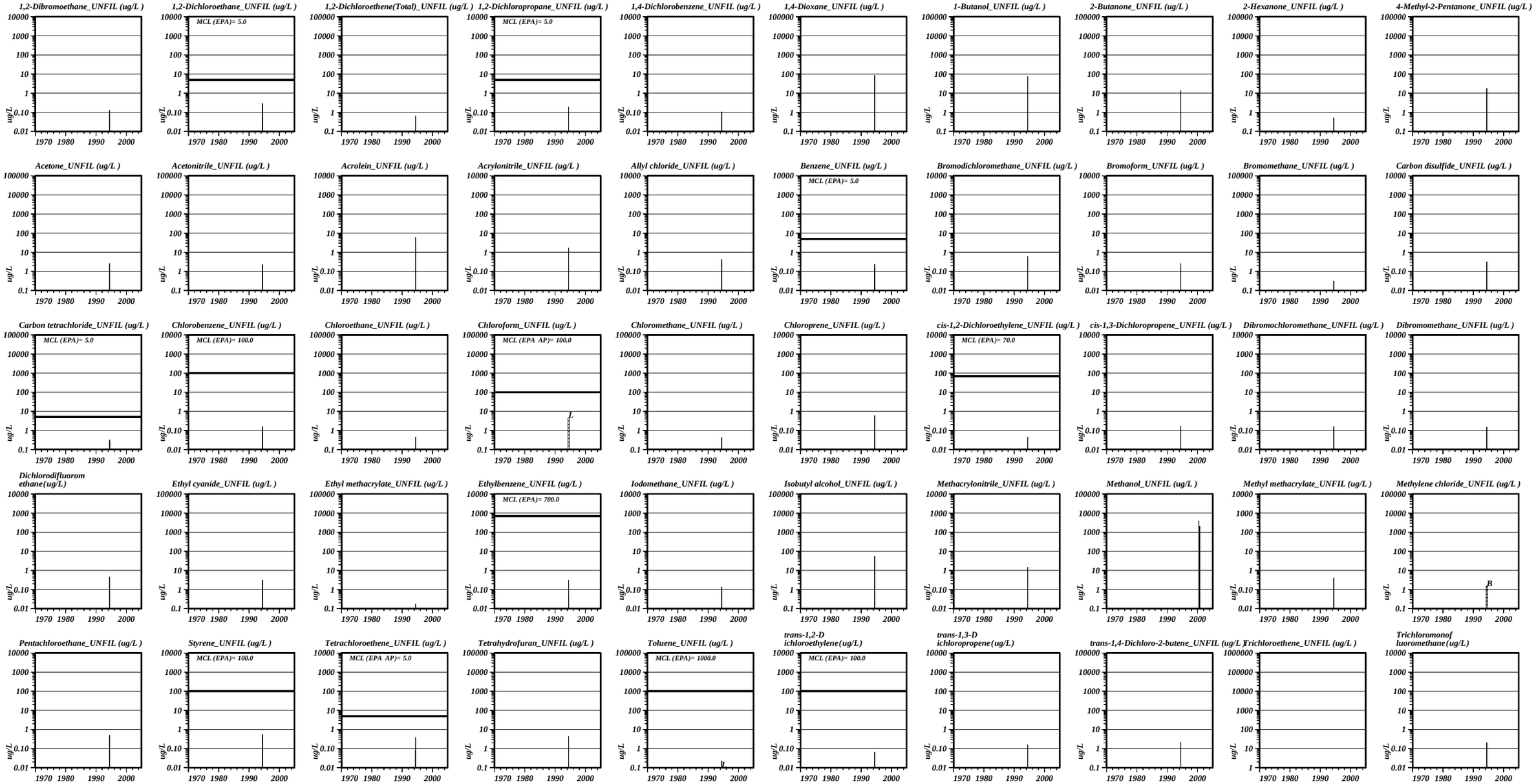
DOE HANFORD SITE - GROUNDWATER QUALITY DATA PLOTS wellseries-100-199 WELL#=199-N-75

VOLATILE ORGANIC COMPOUNDS



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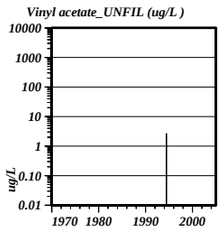
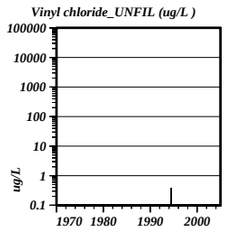
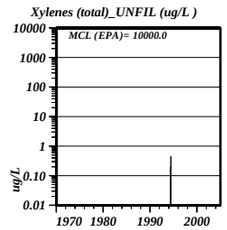
DOE HANFORD SITE - GROUNDWATER QUALITY DATA PLOTS wellseries-100-199 WELL#=199-N-75

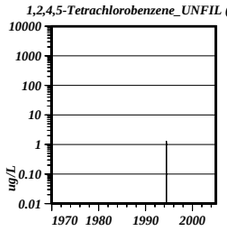
VOLATILE ORGANIC COMPOUNDS

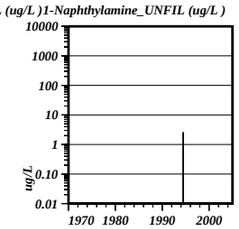


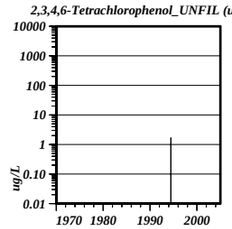


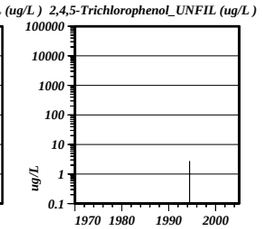


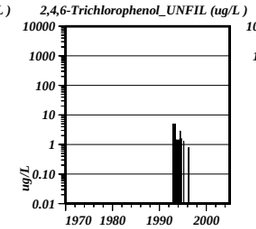
SEMI-VOLATILE ORGANIC COMPOUNDS

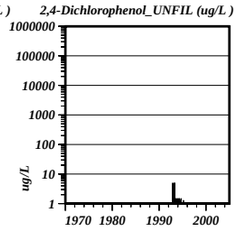


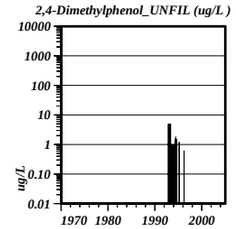


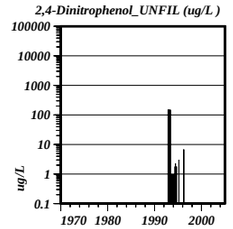


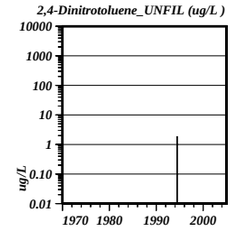


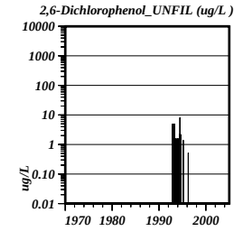


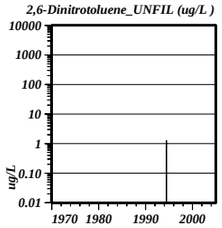


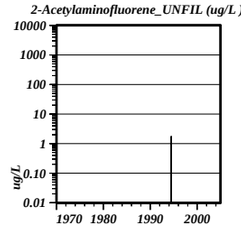


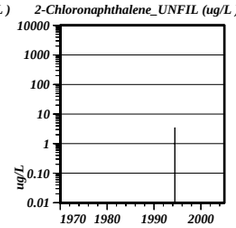


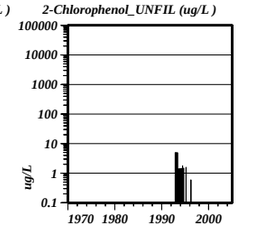


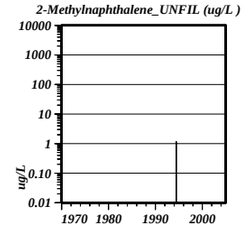


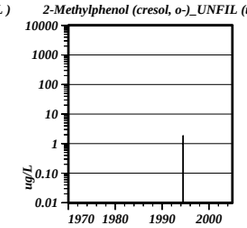


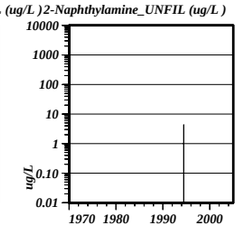


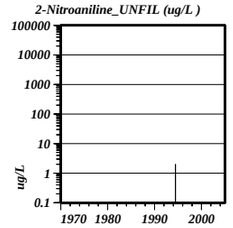


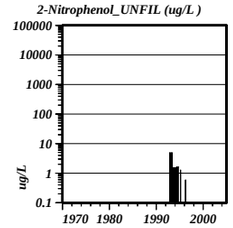


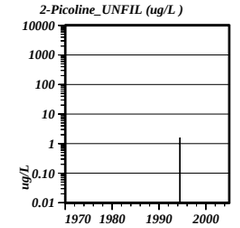


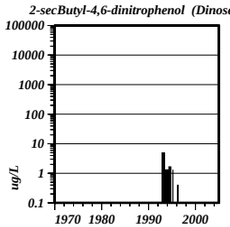


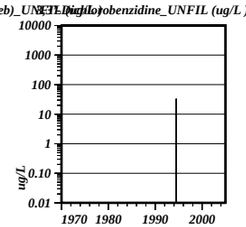


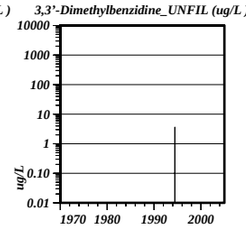


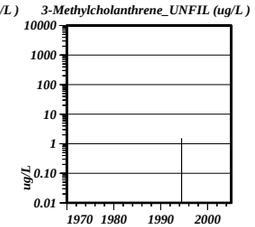


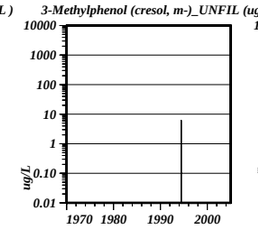


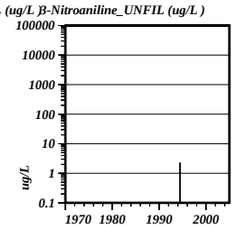


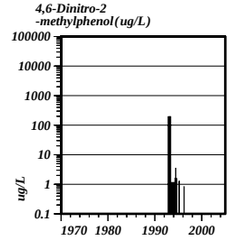


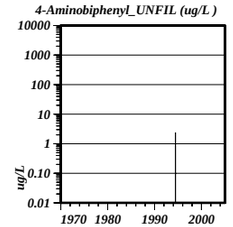


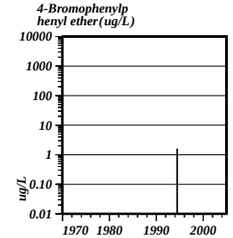


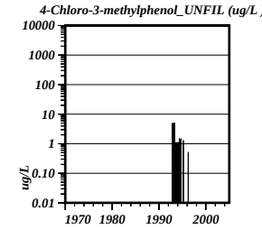


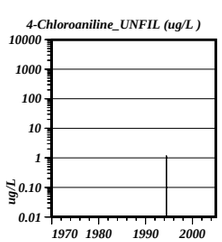


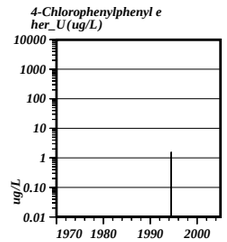


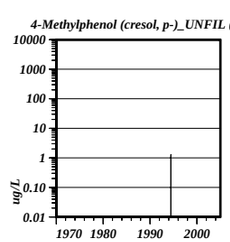


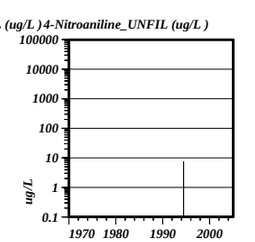


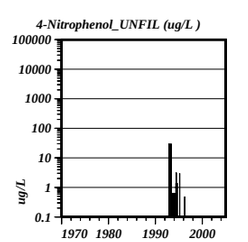


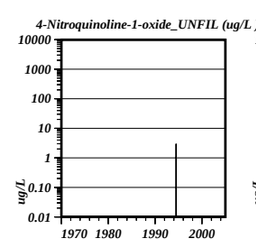


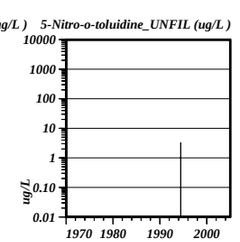


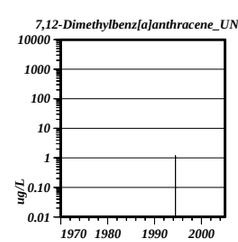


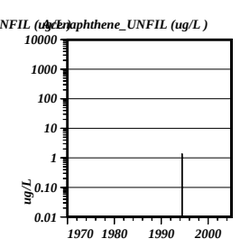


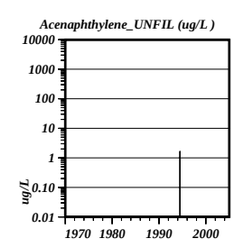












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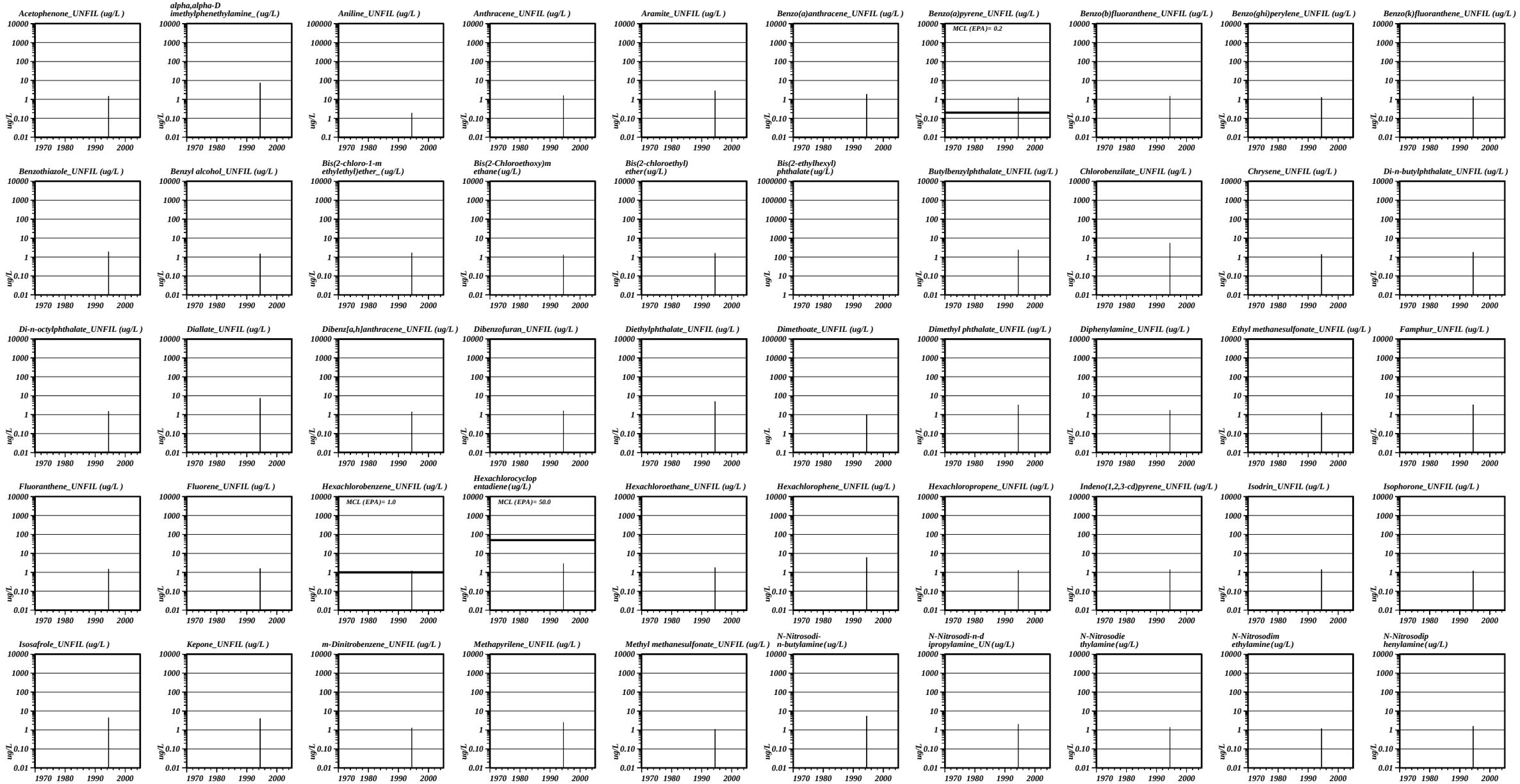
DOE HANFORD SITE - GROUNDWATER QUALITY DATA PLOTS wellseries-100-199 WELL#=199-N-75

SEMI-VOLATILE ORGANIC COMPOUNDS



LABORATORY QUALIFIER FLAGS in HEIS are *, >, B, C, D, E, J, L, P, Q, R, W, X, Y, and Z: Review Document. Main Flags are : J=Estimated value:L=Value between IDL and CRQL (estimated):T=Tentatively identified compound:
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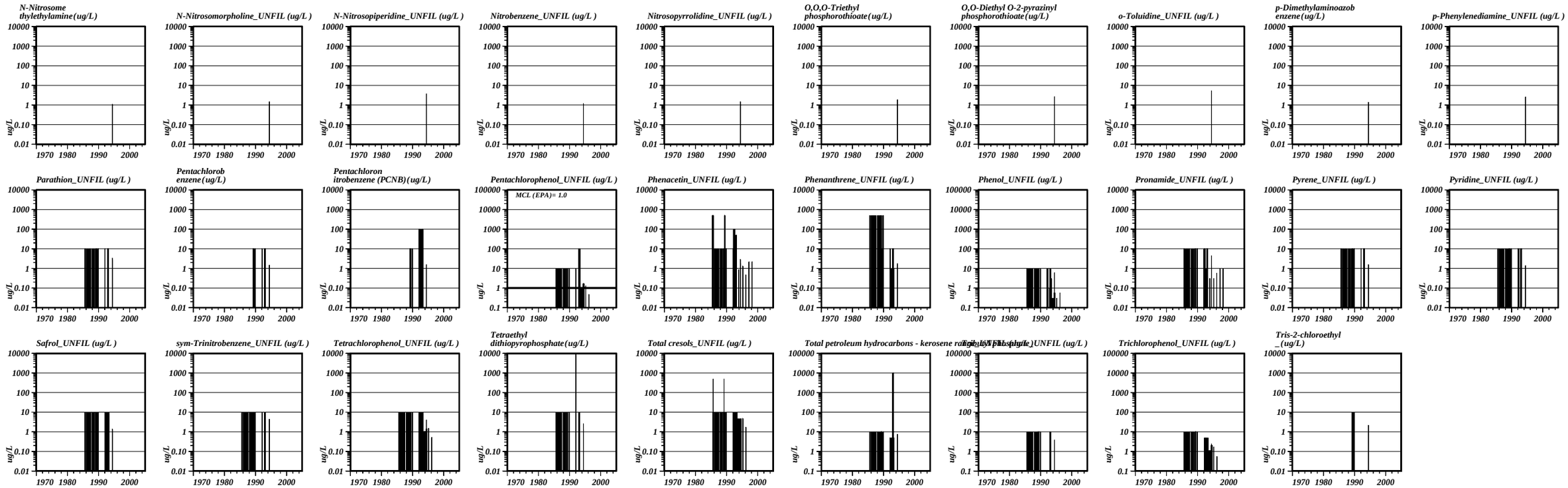
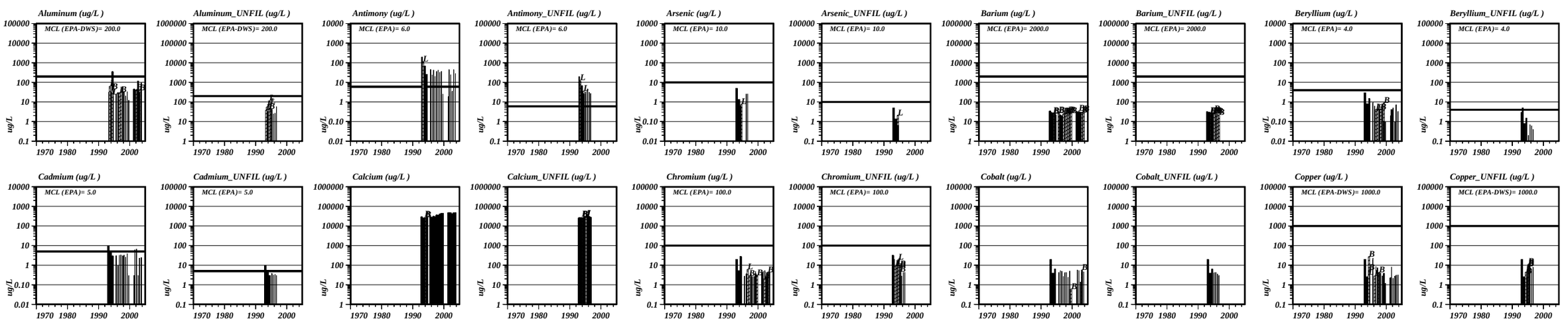
DOE HANFORD SITE - GROUNDWATER QUALITY DATA PLOTS wellseries-100-199 WELL#=199-N-75

SEMI-VOLATILE ORGANIC COMPOUNDS



METALS & PHYSICAL PARAMETERS



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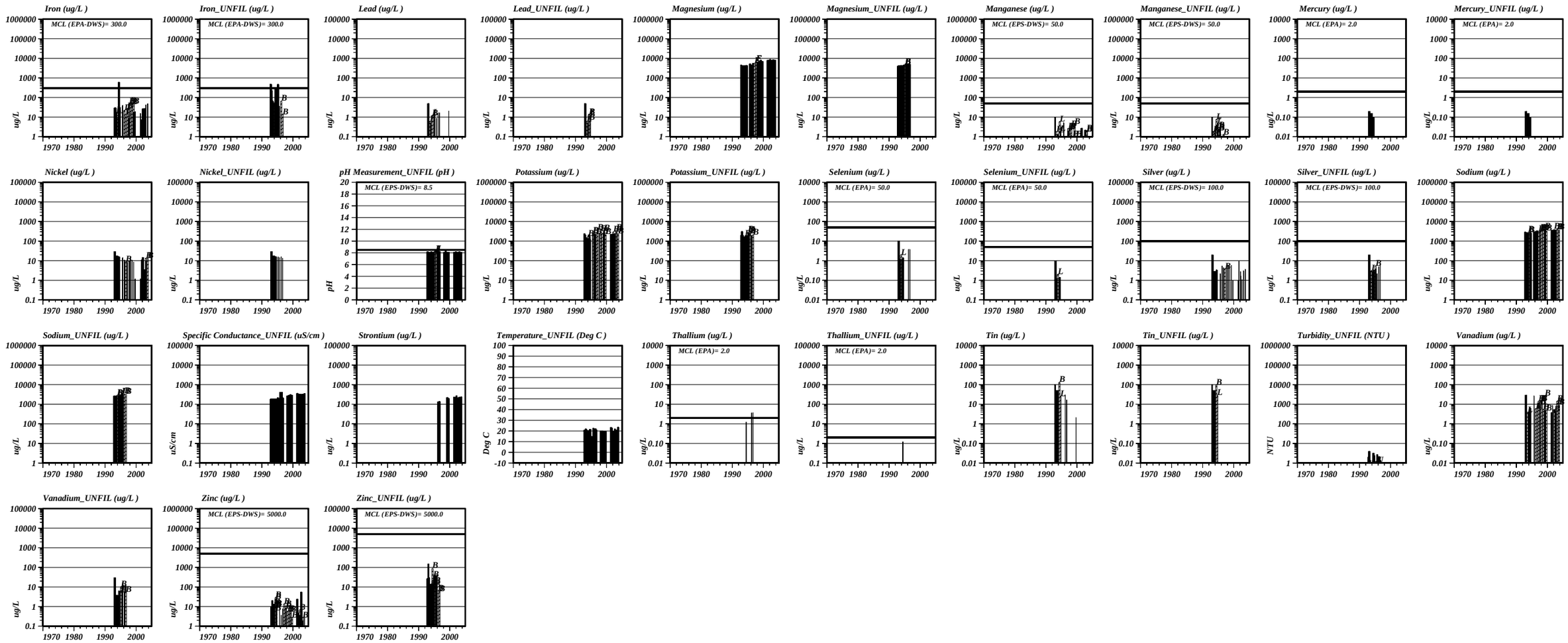
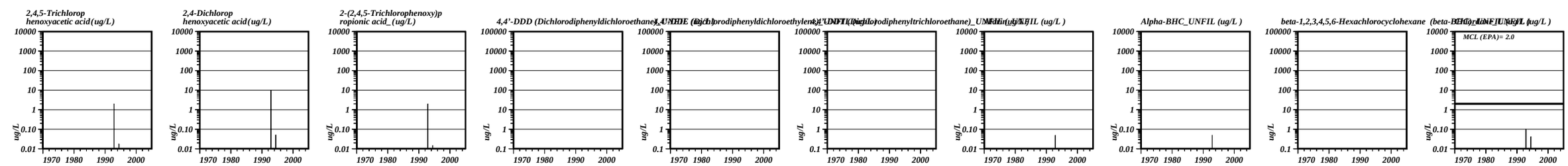
DOE HANFORD SITE - GROUNDWATER QUALITY DATA PLOTS wellseries-100-199 WELL#=199-N-75

METALS & PHYSICAL PARAMETERS



PEST/PCB, HERB, & DIOXINS



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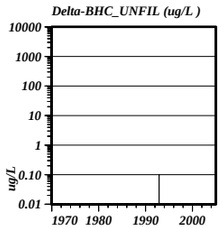
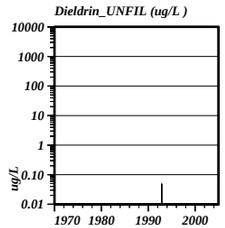
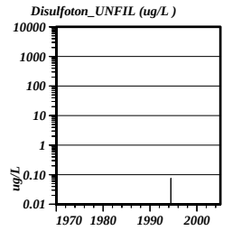
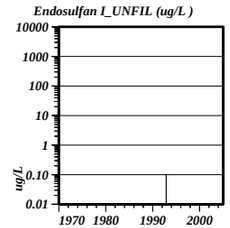
DOE HANFORD SITE - GROUNDWATER QUALITY DATA PLOTS wellseries-100-199 WELL#=199-N-75

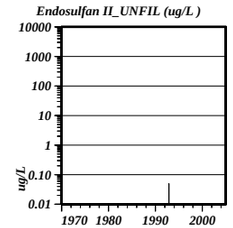
PEST/PCB, HERB, & DIOXINS

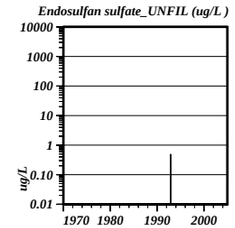


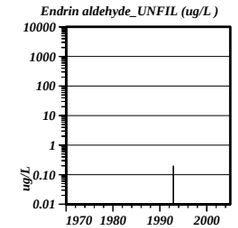


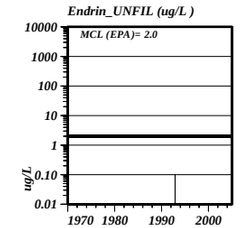


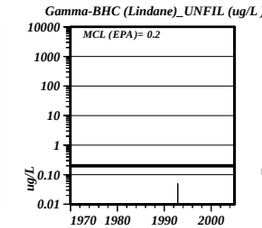


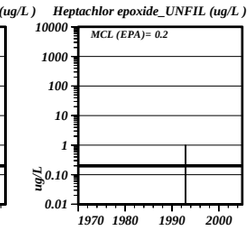


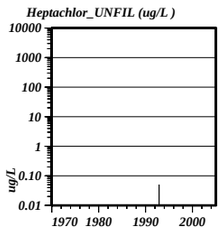


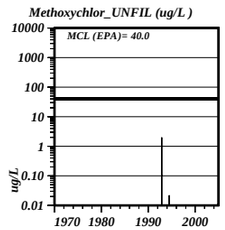


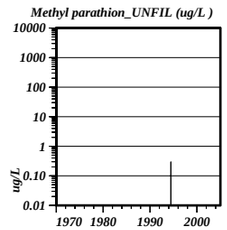


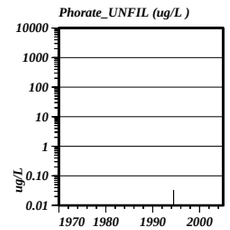


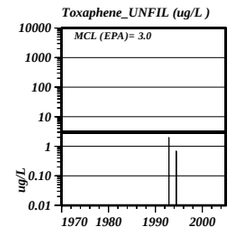




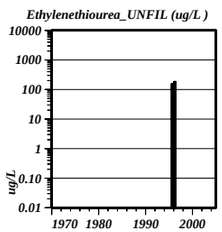


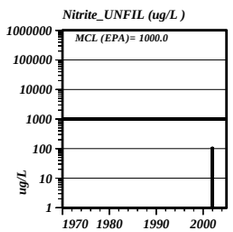


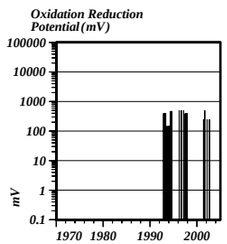




GENCHEM & ORGANICS & GENORGANICS







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